

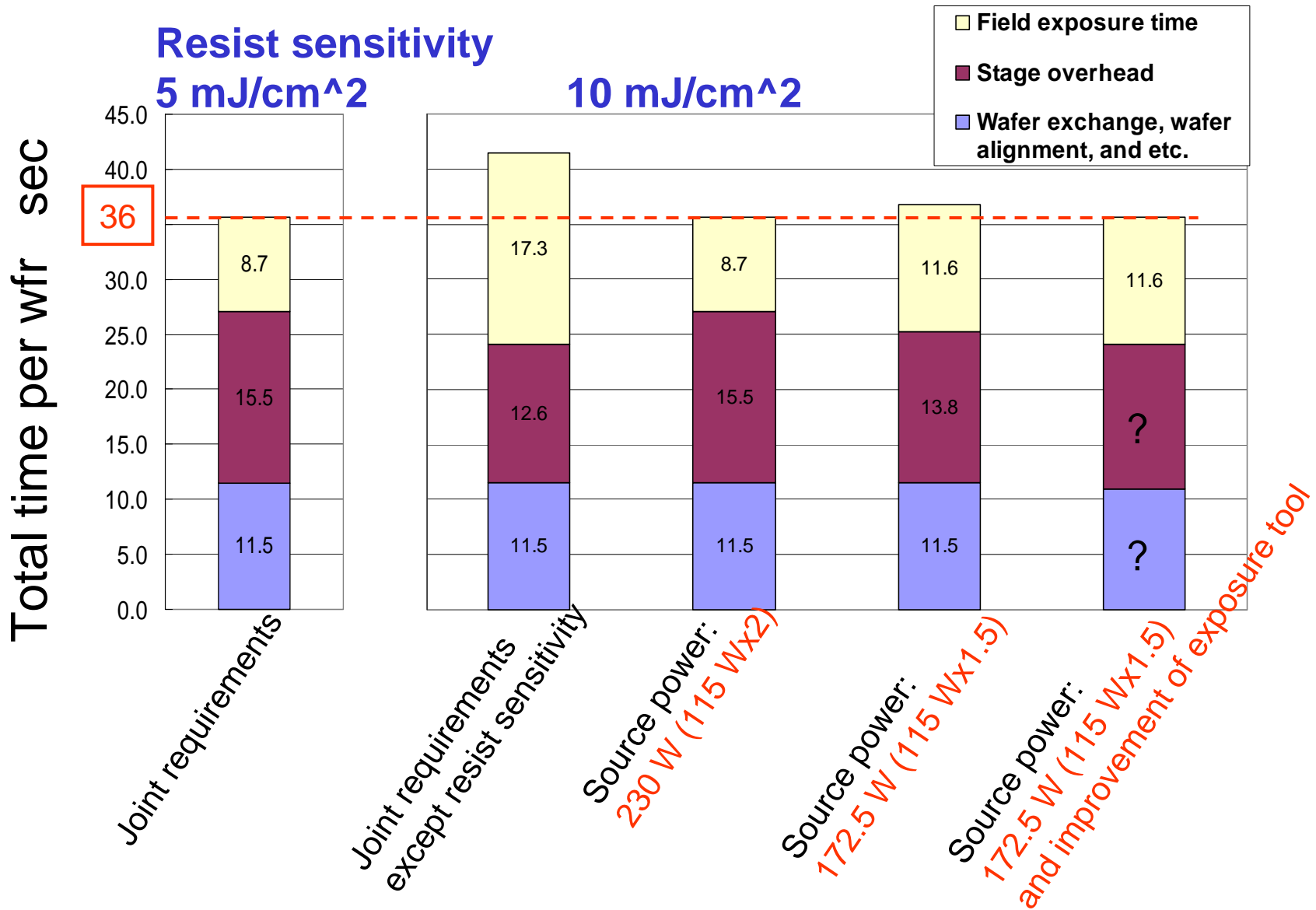
EUV Source Workshop



Panel: Canon's perspective on the present status of resist performance and its effect on EUV source requirements

Hajime Kanazawa
February 27, 2005

Impact of resist sensitivity of 10 mJ



Resist sensitivity 10 mJ/cm²

Total time per wfr sec

